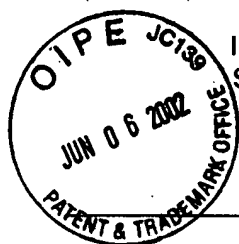


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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,349,587	09/1994	Nadeau-Dostie et al	714	729	
	5,680,543	10/1997	Bhawmik	714	30	
	6,070,260	05/2000	Buch et al	714	731	
	6,195,776	02/2001	Ruiz et al	714	738	
	6,327,684	12/2001	Nadeau-Dostie et al	714	731	

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## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

G. Hetherington et al, "Logic BIST for Large Industrial Designs: Real Issues and Case Studies", Proc., IEEE International Test Conference, Paper No. 142, 1999, pages 358-367.

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